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van de Goor, A.J.; Schanstra, I.; Zorian, Y.;
Memory Technology, Design and Testing, 1994., Records of the IEEE Internat
Workshop on , 8-9 Aug. 1994
Pages:112 - 118

[Abstract]   [PDF Full-Text (528 KB)]   **IEEE CNF**

2 **Fault tolerant and BIST design of a FIFO cell**
Corno, F.; Prinetto, P.; Sonza Reorda, M.;
Design Automation Conference, 1996, with EURO-VHDL '96 and Exhibition,
Proceedings EURO-DAC '96, European , 16-20 Sept. 1996
Pages:233 - 238

[Abstract]   [PDF Full-Text (516 KB)]   **IEEE CNF**

3 **An effective BIST scheme for ring-address type FIFOs**
Zorian, Y.; Van de Goor, A.J.; Schanstra, I.;
Test Conference, 1994. Proceedings., International , 2-6 Oct. 1994
Pages:378 - 387

[Abstract]   [PDF Full-Text (820 KB)]   **IEEE CNF**

4 **Self-checking and fault tolerant approaches can help BIST fault coverage: a case study**
Corno, F.; Prinetto, P.; Sonza Reorda, M.;
European Design and Test Conference, 1996. ED&TC 96. Proceedings , 11-14
March 1996
Pages:610

[Abstract]   [PDF Full-Text (88 KB)]   **IEEE CNF**

---

5 Built in self test for ring addressed FIFOs with transparent latches
Fenstermaker, L.; Ilyoung Kim; Lewandowski, J.; Nagy, J.J.;
Memory Technology, Design and Testing, 1999. Records of the 1999 IEEE
International Workshop on , 9-10 Aug. 1999
Pages:72 - 77

[Abstract]   [PDF Full-Text (28 KB)]   **IEEE CNF**

---

6 A low-power generator-based FIFO using ring pointers and current-mode sensing
Fenstermaker, L.R.; O'Conner, K.J.;
Solid-State Circuits Conference, 1993. Digest of Technical Papers. 40th ISSC(
1993 IEEE International , 24-26 Feb. 1993
Pages:242 - 243, 295

[Abstract]   [PDF Full-Text (460 KB)]   **IEEE CNF**

---

7 Effective march algorithms for testing single-order addressed mem(
van de Goor, A.; Zorian, Y.;
Design Automation, 1993, with the European Event in ASIC Design. Proceedir
[4th] European Conference on , 22-25 Feb. 1993
Pages:499 - 505

[Abstract]   [PDF Full-Text (508 KB)]   **IEEE CNF**

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